



## Announcement

### **7<sup>th</sup> Aerosol training course in Hyytiälä, Finland May 7-13, 2011**

*Measurements of atmospheric aerosols:  
Aerosol physics, sampling and measurement techniques*

The course will cover following aspects for atmospheric aerosol particles: Physical, mechanical, and electrical properties, sampling, filters and impactors, size spectrometers, particle counters, nephelometer, absorption photometers, online mass measurements, aerosol mass spectrometers

Lecturers:

Prof. Dr. Kaarle Hämeri,  
University of Helsinki, Finland (kaarle.hameri@helsinki.fi)

Prof. Dr. Alfred Wiedensohler,  
Leibniz Institute for Tropospheric Research, Leipzig, Germany (ali@tropos.de)  
GAW-World Calibration Centre for Aerosol Physics (WCCAP)

Jean-Philippe Putaud  
Joint Research Centre, Ispra, Italy (jean.putaud@jrc.it)

This course is mainly intended for Ph.D students, young scientist, and personnel from aerosol measuring stations involved in CRAICC, ACTRIS, EUSAAR, GAW, GUAN, and EMEP.

The aerosol course is interactively taught in English. Good English in understanding and speaking is required.

The course is organized within the frame of the EU-project ACTRIS as well as the GAW-WCCAP, iLEAPS, ACTRIS, EUSAAR, the Nordic Graduate School "Biosphere-Carbon-Aerosol-Cloud-Climate Interactions" (CBACCI), and Nordic Master's Degree Programme "Atmosphere-Biosphere-Studies" (ABS), Finnish Centre of Excellence "Physics, Chemistry, Biology and Meteorology of Atmospheric Composition and Climate Change" and in cooperation with Norfa Network on Atmospheric Aerosol Dynamics (NAD).

Participation to the course is free for PhD and MSc students from Nordic and Baltic universities. For the others, a charge of 300 € will be collected to cover the costs of accommodation incl. meals and transport from Helsinki to Hyytiälä field station.

Please, send your application and requests for further information on course contents, travel and accommodation to [kaarle.hameri@helsinki.fi](mailto:kaarle.hameri@helsinki.fi)

**Deadline for applications: March 15, 2011**